

**STATEMENT UNDER 37 CFR 1.97(e) ACCOMPANYING  
INFORMATION DISCLOSURE STATEMENT**

Docket No.  
**14846-36**

In Re Application Of: **Aura Yanavi**

Serial No.  
**TBD**

Filing Date  
**November 20, 2003**

Examiner  
**TBD**

Group Art Unit  
**TBD**

Invention: **Methods and Systems For Predicting Software Defects In An Upcoming Software Release**

**TO THE COMMISSIONER FOR PATENTS:**

This is a statement under the provisions of 37 CFR 1.97(e) in the above-identified application.

Check applicable statement herebelow:

**Statement Under 37 CFR 1.97(e)(1)**

- Each item of information contained in the accompanying Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the Information Disclosure Statement.

**Statement Under 37 CFR 1.97(e)(2)**

- No item of information contained in the accompanying Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application, and, to the knowledge of the undersigned person, after making reasonable inquiry, no item of information contained in the accompanying Information Disclosure Statement was known to any individual designated in 37 CFR 1.56(c) more than three months prior to the filing of the Information Disclosure Statement.



*George Morgan*  
Signature

Dated: **November 20, 2003**

George Morgan, (Reg. No. 46,505)  
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*Kelly Billingsley*  
Signature of Person Mailing Correspondence

**Kelly Billingsley**

**Typed or Printed Name of Person Mailing Correspondence**

cc:

**INFORMATION DISCLOSURE CITATION**  
*(Use several sheets if necessary)*

ATTY DOCKET NO.  
**14846-36**

SERIAL NO.

**TBA**

**Methods and Systems For Predicting Software Defects.....**

FILING

GROUP

November 20, 2003

**TBA**

**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		<b>US 6,073,107</b>	<b>06/06/00</b>	Minkiewicz et al.			
		<b>US 6,477,471</b>	<b>11/05/02</b>	Hedstrom et al.			
		<b>US 6,546,506</b>	<b>04/08/03</b>	Lewis			
		<b>US 5,446,895</b>	<b>08/29/95</b>	White et al.			
		<b>US 5,655,074</b>	<b>08/05/97</b>	Rauscher			
		<b>US 5,758,061</b>	<b>05/26/98</b>	Plum			
		<b>US 5,903,897</b>	<b>05/11/99</b>	Carrier III et al.			
		<b>US 5,960,196</b>	<b>09/28/99</b>	Carrier III et al.			
		<b>US 6,363,524</b>	<b>03/26/02</b>	Loy			
		<b>US 6,405,364</b>	<b>06/11/02</b>	Bowman-Amuah			
		<b>US 6,513,154</b>	<b>01/28/03</b>	Porterfield			

**FOREIGN PATENT DOCUMENTS**

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

**OTHER DOCUMENTS** *(Including Author, Title, Date, Pertinent Pages, Etc.)*

Hudepohl, J.P., et al., "Integrating Metrics and Models For Software Risk Assessment," p. 93, The Seventh International Symposium on Software Reliability Engineering (ISSRE'96) October 30-November 02, 1996, White Plains, NY (Abstract)

Levendel, Y., "Reliability Analysis of Large Software Systems: Defect Data Modeling," pp. 141-152, IEEE Transactions on Software Engineering (Abstract)

EXAMINER	DATE CONSIDERED
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		US 6,519,763	02/11/03	Kaufer et al.			
		US 6,601,017	07/29/03	Kennedy et al.			
		US 6,601,018	07/29/03	Logan			
		US 6,601,233	07/29/03	Underwood			
		US 6,626,953	09/30/03	Johndrew et al.			
		US 6,629,266	09/30/03	Harper et al.			
		US 2002/0147961	10/10/02	Charters et al.			
		US 2002/0162090	10/31/02	Parnell et al.			
		US 2003/0018952	01/23/03	Roetzheim			
		US 2003/0033586	02/13/03	Lawler			
		US 2003/0188290	10/02/03	Corral			

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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

		Yu, T.J., et al., "An Analysis of Several Software Defect Models," pp. 1261-1270, IEEE Transactions on Software Engineering (Abstract)
		Wohlin, C., et al., "Understanding the Sources of Software Defects: A Filtering Approach; 8th International Workshop on Program Comprehension (IWPC'00), June 10-11, 2000 (Abstract)

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